Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/711,959	HENG ET AL.
Examiner	Art Unit
Phallaka Kik	2825

SEARCHED				
Class	Subclass	Date	Examiner	
716	3,2,9,10	12/26/2006	PK	
Above	updated	4/9/2007	PK	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
BRS (EAST)USPAT, USPGPUB New search Class/sub searched: 716/1-18 (see attached)	12/26/2006	PK	
Above updated (see attached)	4/9/2007	PK	
IEE/IEEE Xplore new search (see attached)	12/26/2006	PK	
EPO, JPO, IBM TDB, Derwent new search (see attached)	12/26/2007	PK	
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